



COLLEGES OF NANOSCALE
SCIENCE AND ENGINEERING
SUNY POLYTECHNIC INSTITUTE

Scaling Options in Relation to 450mm

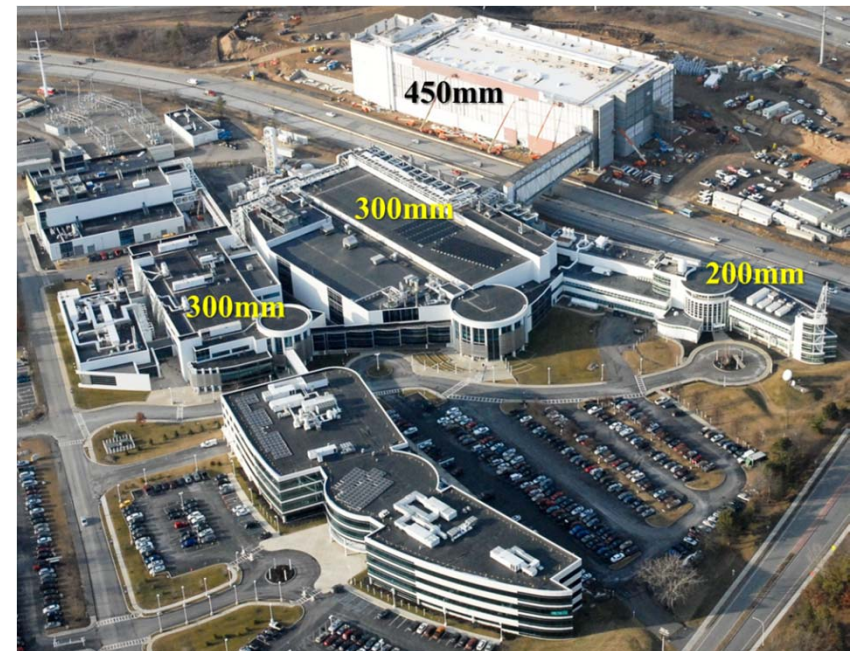
October 8, 2014

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Agenda

- ▣ Introduction
- ▣ Lithography
- ▣ 450 mm
- ▣ 3Di/Packaging
- ▣ Other semiconductors





Environment

- Smart phones surpass PCs in chip sales

- Leading-edge industry consolidation

- Foundries; IDMs
- Equipment suppliers

- How far/fast will scaling continue?

- Continued scaling is cost driven

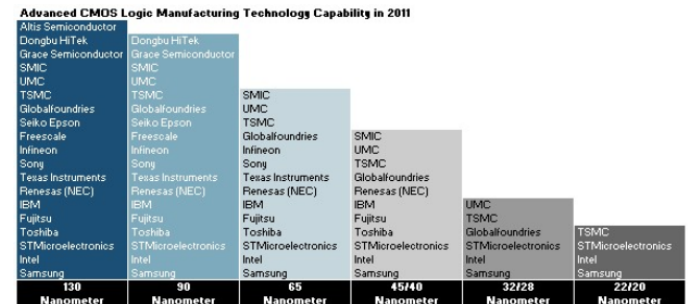
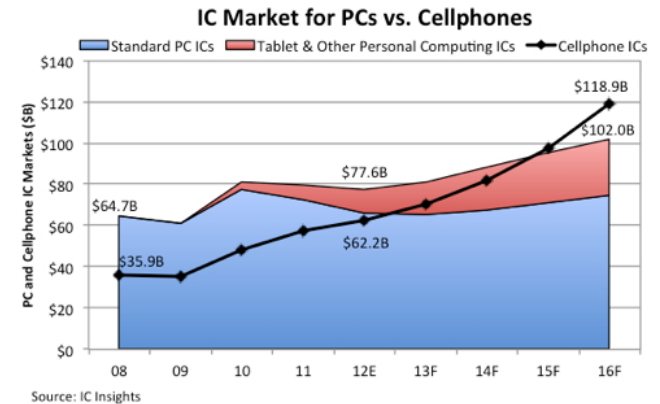
(A.Manocha; Semicon West 2013)

Based On SRAM Size & Other Information Seen In Our Consulting Work,
In Our View The "14nm" Nodes From Each Manufacturer Should Be
Called:

- ◆ Intel – 16nm or 17nm
- ◆ Samsung – 18nm
- ◆ TSMC & GF – 20nm
- ◆ STM – 21nm

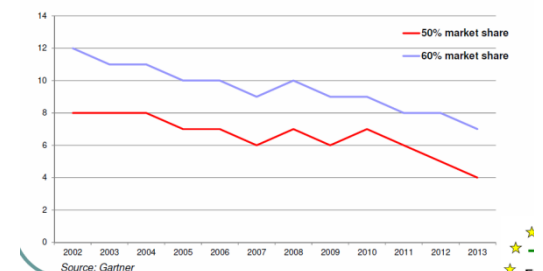
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(Future Horizons, Semicon Europa 2013)



IHS iSuppli Research

Number of equipment suppliers providing cumulative market share of ≥ 50/60% of total market

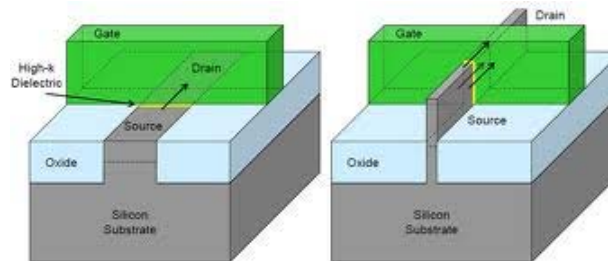




How can Moore's Law be extended?

• Performance / Power Consumption

- New materials
- New devices
- New architectures

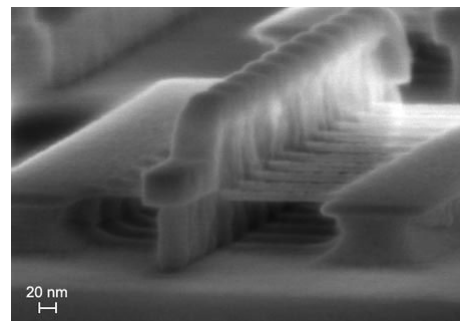


www.semiwiki.com

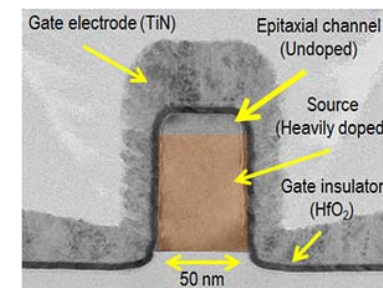
Source: IBM

• Cost

- Lithographic scaling
- Wafer size scaling
- Chip stacking "3D"



<http://spectrum.ieee.org>



<http://phys.org/news>



How can Moore's Law be extended?

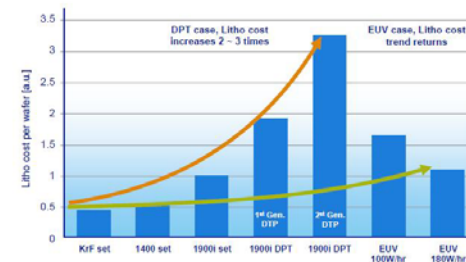
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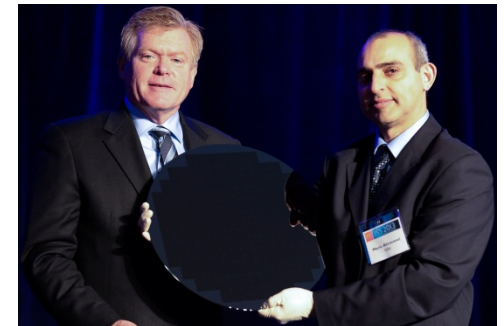
- **Cost**

- Lithographic scaling
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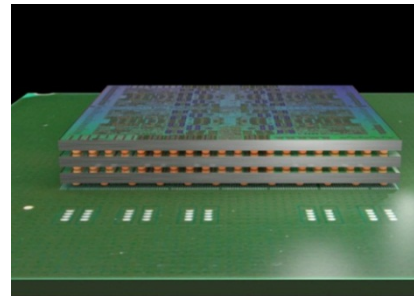
Litho costs back to normal with EUV >100 W/hr



Source: Samsung, Prague, Oct 2009



<http://450mm.com>



<http://ibmresearchnew.blogspot.com>



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- ▣ **Lithography and materials**
- ▣ 450 mm
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CNSE Albany Silicon Capabilities

- Full complement of 300 mm wafer tools
 - ✓ Leading-edge lithography
 - ✓ Backwards compatible to 65 nm; license
- Used today for 10-7 nm CMOS development
 - ✓ CNSE is a joint development partner
- Capacity of ~30 integrated wafer starts per day
 - ✓ 24/7 operation
- 1st 450mm tool set in the industry





Lithography Industry Challenges

□ 193nm Cannot Meet Requirements for Scaled “7nm”

□ 10nm Uses Patterning Tricks to Extend 193 Capability

▣ Smaller CD but increasingly complex

- Multiple-Pass Litho / Litho-Etch-Litho-Etch
- Self-Aligned Double Patterning (Sidewall Image Transfer)
- Source Mask Optimization Restrictions



Complexity



Variability



Design Limits

□ EUV Is Simpler and *Potentially* Cheaper @ 7nm Node

▣ Min Feature Size ~15nm

▣ Simplified Patterning

- Single-Pass Litho Reduces Mask Count
- Single SIT Processes
- Wider Process Window
- Bi-Directional Printing Possible



Variability



Complexity



Defectivity



Design Limits



EUV Lithography Program

EUV is gated by scanner productivity

- A throughput of above 100 wafers/hr. is considered sufficient

Other key infrastructure items

- Actinic defect inspection (SEMATECH EMI program)
- Mask blank development (SEMATECH mask blank center)
- Resist Enablement Center access to MET and EUV full field
- Mask pellicle need / development



ASML 3300
at CNSE



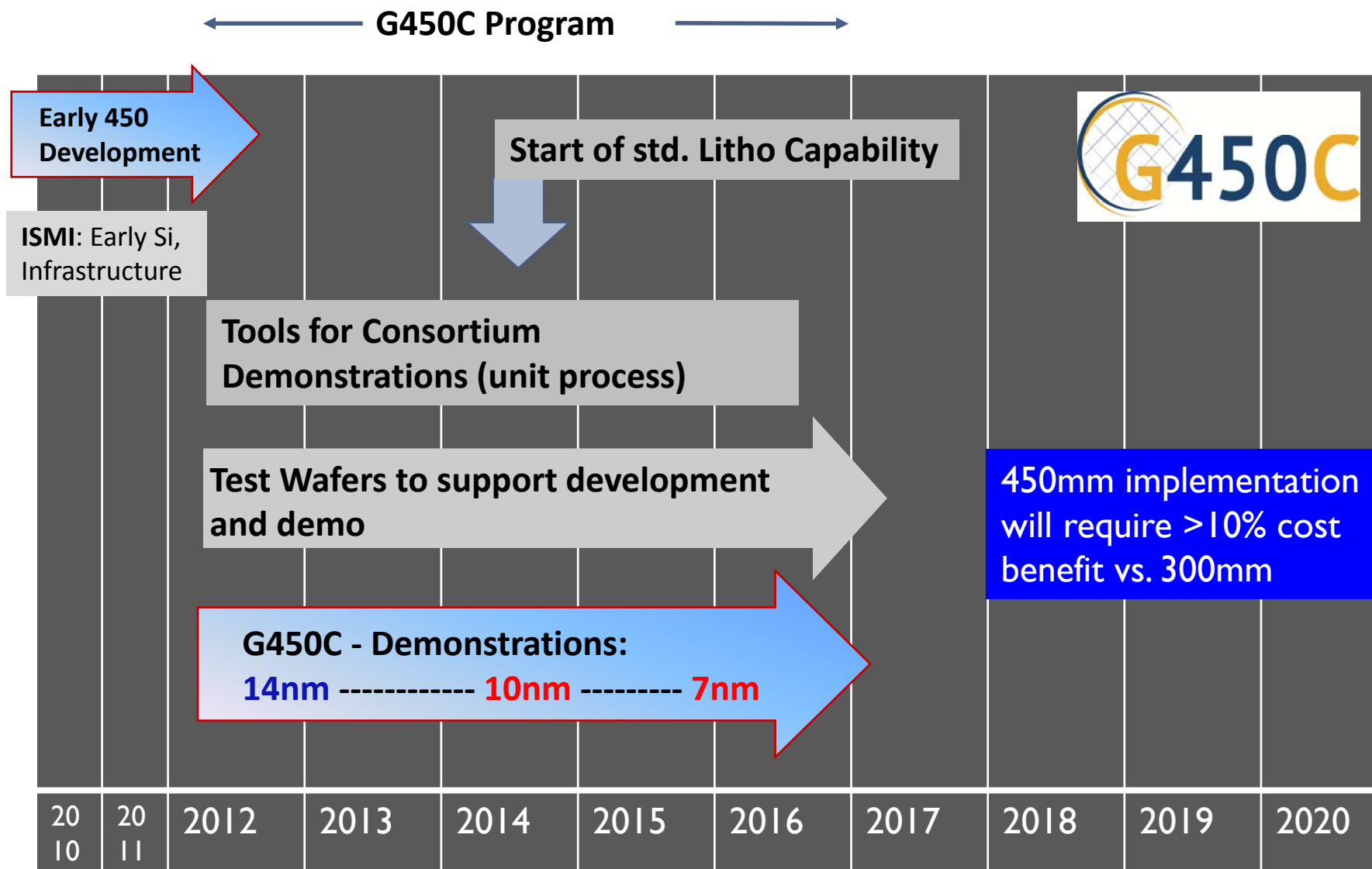
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Development and Technology Intercept Targets





Agenda

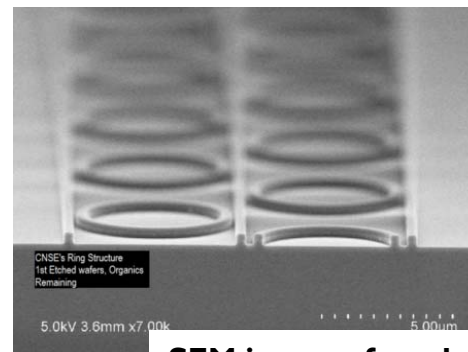
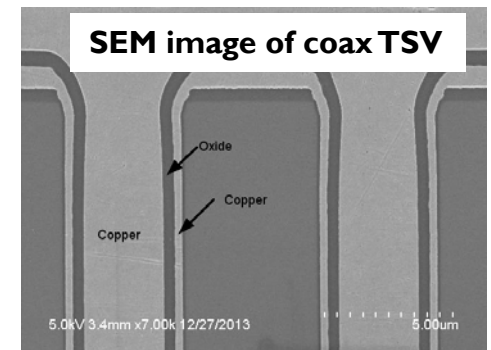
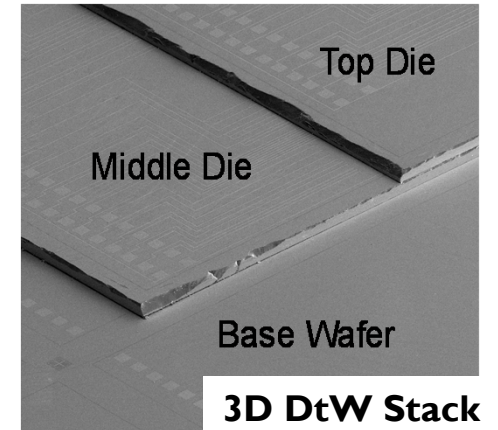
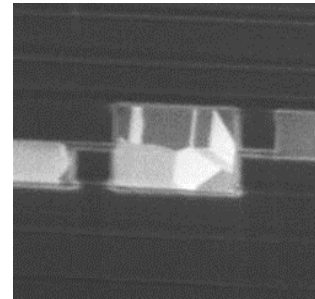
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3D Integration @ CNSE

- Full 2.5D/3D integrated process developed and implemented
 - 3D DtW and WtW bonding
 - Mid-via integration in 65 nm CMOS
 - Fully customer tape-out ready
-
- Currently used, e.g., for integrated photonics on interposer



SEM image of modulator



- **NYS Funded Packaging Facility**
 - RFE 10/15/2014
- **Technology Center for Standard and Advanced Packaging Manufacturing**
 - Provide packaging R&D consortia option for companies to interact and develop business opportunities
 - Offer quick turn facility for customer packaging applications

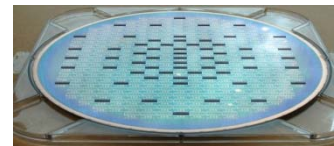


South West Corner



□ Top three process and equipment-related issues in 3D:

1. *Cost*
2. *Cost*
3. *Cost*
4. No standards



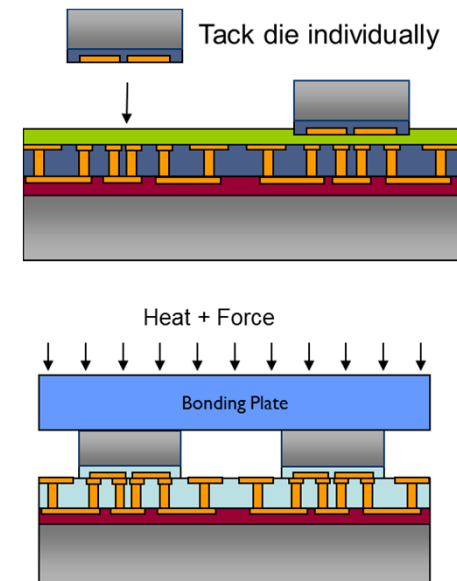
□ Die-Wafer

- ▣ Speed of die attach process / tooling
- ▣ Die level tracking
- ▣ Process control

□ Wafer-Wafer

- ▣ KGD – test and overall yield
- ▣ Die size matching

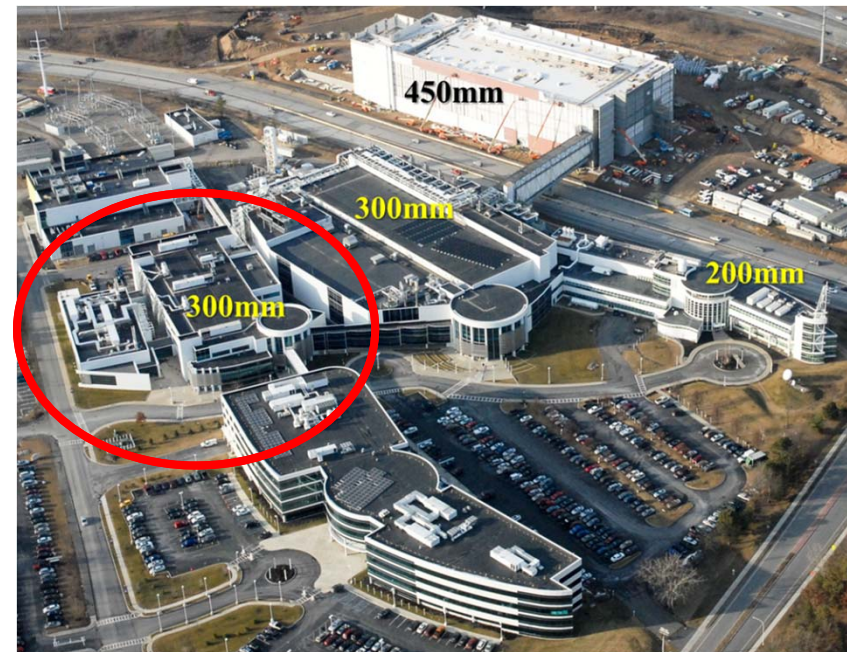
□ Alternatives?





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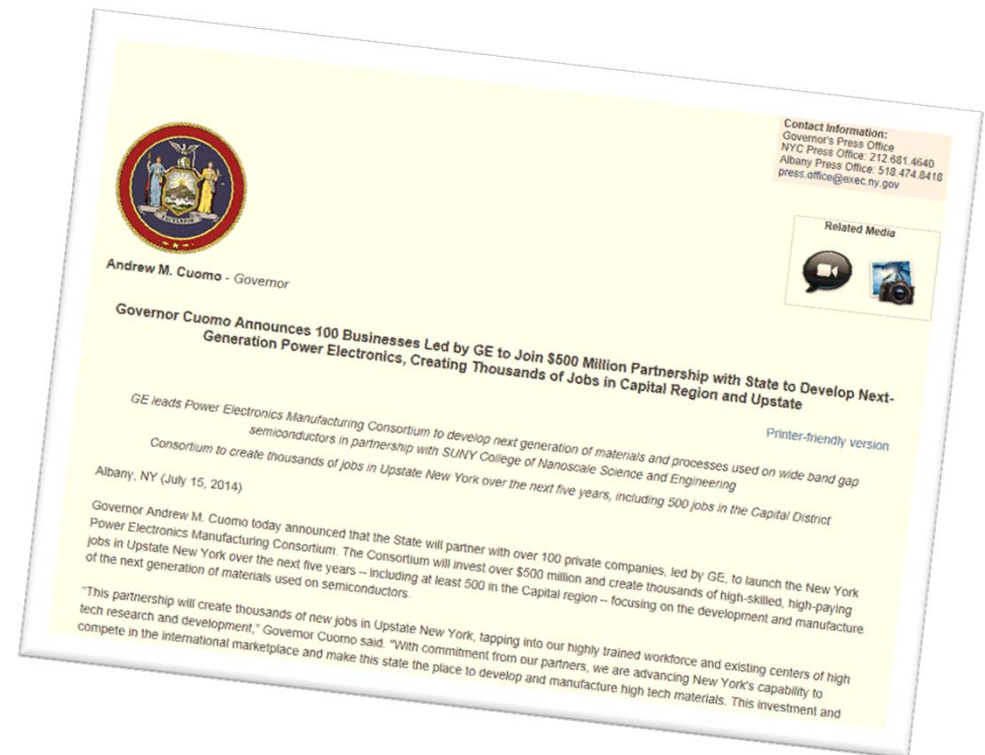
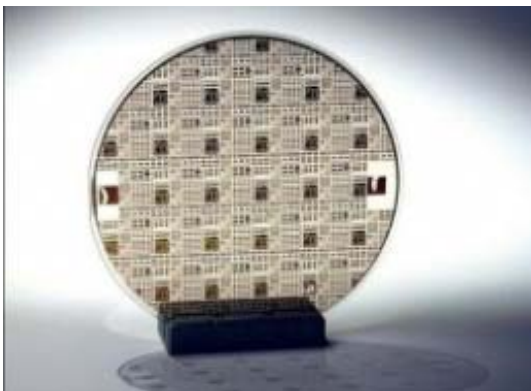




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imagination at work



Initial fab capacity 10k wafers/yr
Total fab output up to 1TVA/yr

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Summary



- The cost component of Moore's law is running into head winds
- The most significant options to continue manufacturing scaling:
 1. EUV still has cost and infrastructure challenges to overcome
 2. The transition to 450mm is projected toward the end of the decade
 3. Chip stacking lacks standards and manufacturing cost issues remain
- Many applications require less aggressive scaling
 - Alternate substrates



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THANK YOU

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